

December 2008

# FDFMA2P853T

# Integrated P-Channel PowerTrench® MOSFET and Schottky Diode

**–20 V, –3.0 A, 120 m**Ω

### **Features**

#### MOSFET:

- Max  $r_{DS(on)}$  = 120 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -3.0 A
- Max  $r_{DS(on)} = 160 \text{ m}\Omega$  at  $V_{GS} = -2.5 \text{ V}$ ,  $I_D = -2.5 \text{ A}$
- Max  $r_{DS(on)}$  = 240 m $\Omega$  at  $V_{GS}$  = -1.8 V,  $I_D$  = -1.0 A

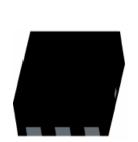
### Schottky:

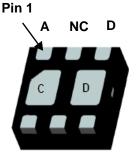
- V<sub>F</sub> < 0.46 V @ 500 mA
- Low profile 0.55 mm maximum in the new package MicroFET 2x2 **Thin**
- RoHS Compliant
- Free from halogenated compounds and antimony oxides

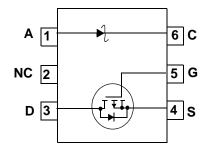
## **General Description**

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features a MOSFET with low on-state resistance and an independently connected low forward voltage schottky diode for minimum conduction losses.

The MicroFET 2x2 **Thin** package offers exceptional thermal performance for it's physical size and is well suited to linear mode applications.







MicroFET 2X2 Thin C G S

# MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage		-20	V
$V_{GS}$	Gate to Source Voltage		±8	V
1	Drain Current -Continuous T <sub>A</sub> = 25 °C	(Note 1a)	-3.0	۸
<sup>I</sup> D	-Pulsed		-6	— A
D	Power Dissipation T <sub>A</sub> = 25 °C	(Note 1a)	1.4	W
$P_{D}$	Power Dissipation T <sub>A</sub> = 25 °C	(Note 1b)	0.7	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C
$V_{RRM}$	Schottky Repetitive Peak Reverse Voltage		30	V
Io	Schottky Average Forward Current		1	Α

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	86	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	173	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1c)	86	*C/VV
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1d)	140	

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
53	FDFMA2P853T	MicroFET 2x2 Thin	7 "	8 mm	3000 units

# **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

Parameter	Test Conditions	Min	Тур	Max	Units
acteristics					
Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu A$ , referenced to 25 °C		-12		mV/°C
Zero Gate Voltage Drain Current	V <sub>DS</sub> = -16 V, V <sub>GS</sub> = 0 V			-1	μΑ
Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, \ V_{DS} = 0 \text{ V}$			±100	nA
	Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current	acteristicsDrain to Source Breakdown Voltage $I_D = -250 \mu A$ , $V_{GS} = 0 V$ Breakdown Voltage Temperature Coefficient $I_D = -250 \mu A$ , referenced to 25 °CZero Gate Voltage Drain Current $V_{DS} = -16 V$ , $V_{GS} = 0 V$	Cacteristics         Drain to Source Breakdown Voltage $I_D = -250 \mu A$ , $V_{GS} = 0 V$ $-20$ Breakdown Voltage Temperature Coefficient $I_D = -250 \mu A$ , referenced to 25 °C         Zero Gate Voltage Drain Current $V_{DS} = -16 V$ , $V_{GS} = 0 V$	Cteristics         Drain to Source Breakdown Voltage $I_D = -250 \mu A$ , $V_{GS} = 0 V$ $-20$ Breakdown Voltage Temperature Coefficient $I_D = -250 \mu A$ , referenced to 25 °C $-12$ Zero Gate Voltage Drain Current $V_{DS} = -16 V$ , $V_{GS} = 0 V$	Cteristics         Drain to Source Breakdown Voltage $I_D = -250 \mu A$ , $V_{GS} = 0 V$ -20         Breakdown Voltage Temperature Coefficient $I_D = -250 \mu A$ , referenced to 25 °C       -12         Zero Gate Voltage Drain Current $V_{DS} = -16 V$ , $V_{GS} = 0 V$ -1

### **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.7	-1.3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$ , referenced to 25 °C		2		mV/°C
		$V_{GS} = -4.5 \text{ V}, I_D = -3.0 \text{ A}$		90	120	
	Static Drain to Source On Resistance	$V_{GS} = -2.5 \text{ V}, I_D = -2.5 \text{ A}$		120	160	
r <sub>DS(on)</sub>		$V_{GS} = -1.8 \text{ V}, I_D = -1.0 \text{ A}$		172	240	mΩ
		$V_{GS} = -4.5 \text{ V}, I_D = -3.0 \text{ A}$ $T_J = 125 ^{\circ}\text{C}$		118	160	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -3.0 \text{ A}$		7		S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 40.V V 0.V	435	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$	80	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1.0 10112	45	pF

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		9	18	ns
t <sub>r</sub>	Rise Time	$V_{DD} = -10 \text{ V}, I_{D} = -1.0 \text{ A}$	11	19	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$	15	27	ns
t <sub>f</sub>	Fall Time		6	12	ns
$Q_{g(TOT)}$	Total Gate Charge	V 40.V 1 0.0 A	4	6	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DD} = -10 \text{ V}, I_D = -3.0 \text{ A}$ $V_{GS} = -4.5 \text{ V}$	0.8		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	v GS = -4.5 v	0.9		nC

### **Drain-Source Diode Characteristics**

Is		Maximum Continuous Drain-Source Diode Forward Current				-1.1	Α
V	SD	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -1.1 \text{ A}$ (Note 2)		-0.8	-1.2	V
t <sub>rr</sub>		Reverse Recovery Time	I <sub>E</sub> = -3.0 A, di/dt = 100 A/μs		17		ns
Q	rr	Reverse Recovery Charge	$T_F = -3.0 \text{ A}$ , $di/dt = 100 \text{ A/}\mu\text{S}$		6		nC

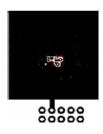
### **Schottky Diode Characteristics**

1_	Reverse Leakage	V <sub>R</sub> = 5 V	T <sub>J</sub> = 25 °C	9.9	50	μΑ
<sup>I</sup> R	Neverse Leakage	v <sub>R</sub> = 5 v	T <sub>J</sub> = 125 °C	2.3	10	mA
			T <sub>J</sub> = 25 °C	9.9	100	μΑ
$I_R$	Reverse Leakage	V <sub>R</sub> = 20 V	T <sub>J</sub> = 85 °C	0.3	1	mA
			T <sub>J</sub> = 125 °C	2.3	10	mA
$V_{F}$	Forward Voltage	I <sub>F</sub> = 500 mA	T <sub>J</sub> = 25 °C	0.4	0.46	V
V F	Forward voltage	IF = 300 IIIA	T <sub>J</sub> = 125 °C	0.3	0.35	V
V	Forward Voltage	I <sub>F</sub> = 1 A	T <sub>J</sub> = 25 °C	0.5	0.55	V
V <sub>F</sub>	Tolward vollage	IF = I A	T <sub>J</sub> = 125 °C	0.49	0.54	V

### Electrical Characteristics T<sub>A</sub> = 25 °C unless otherwise noted

#### Notes

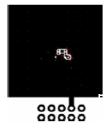
- 1:  $R_{\theta JA}$  is determined with the device mounted on a 1 in<sup>2</sup> oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta JA}$  is determined by the user's board design.
  - (a) MOSFET  $R_{\theta JA} = 86$  °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB.
  - (b) MOSFET  $R_{\theta JA}$  = 173 °C/W when mounted on a minimum pad of 2 oz copper.
  - (c) Schottky  $R_{\theta JA} = 86$  °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper, 1.5 " x 1.5 " x 0.062 " thick PCB.
  - (d) Schottky  $R_{\theta JA}$  = 140  $^{o}\text{C/W}$  when mounted on a minimum pad of 2 oz copper.



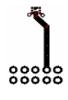
a)86 °C/W when mounted on a 1 in² pad of 2 oz copper.



b)173 °C/W when mounted on a minimum pad of 2 oz copper.



c)86 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



d)140 °C/W when mounted on a minimum pad of 2 oz copper.

2: Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%.

### Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

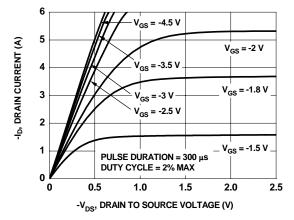


Figure 1. On-Region Characteristics

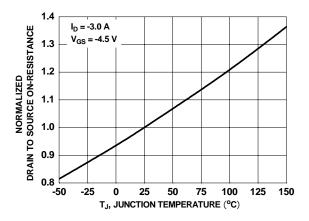


Figure 3. Normalized On-Resistance vs Junction Temperature

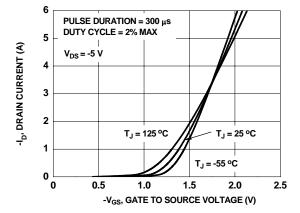


Figure 5. Transfer Characteristics

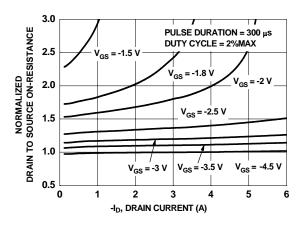


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

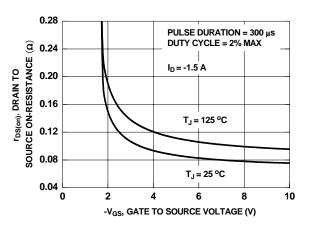


Figure 4. On-Resistance vs Gate to Source Voltage

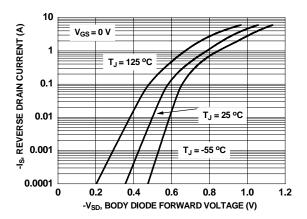


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

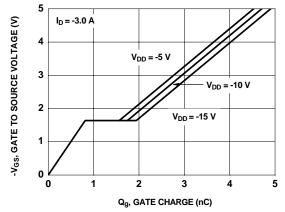


Figure 7. Gate Charge Characteristics

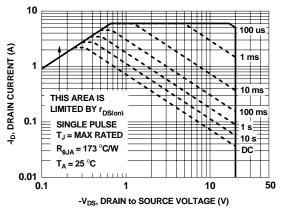


Figure 9. Forward Bias Safe Operating Area

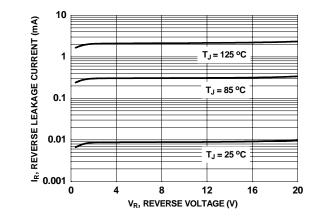


Figure 11. Schottky Diode Reverse Current

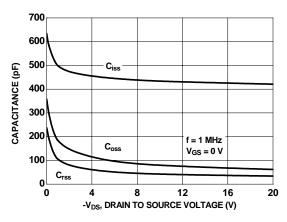


Figure 8. Capacitance vs Drain to Source Voltage

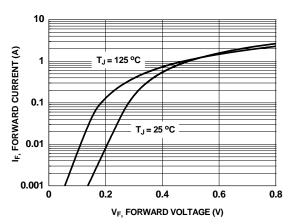


Figure 10. Schottky Diode Foward Voltage

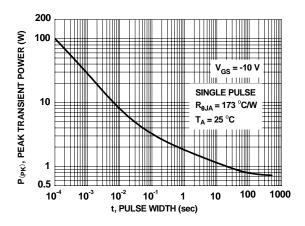


Figure 12. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

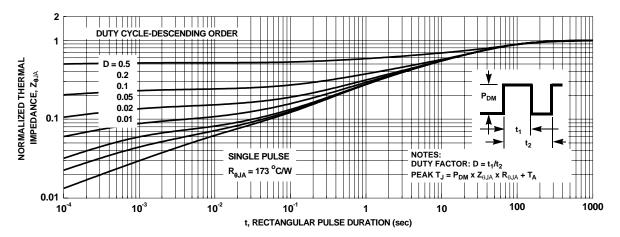
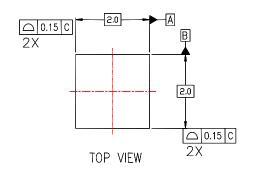
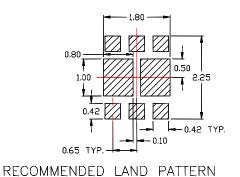
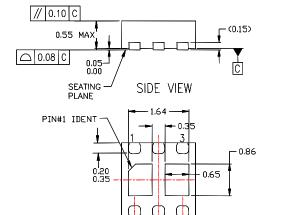


Figure 13. Junction to Ambient Transient Thermal Response Curve

# **Dimensional Outline and Pad Layout**







BOTTOM VIEW

0.25~0.35

1.30 0.10(M)|C|A|B|

### NOTES:

A. NON CONFORMS TO JEDEC REGISTRATION MO-288,

0.65

- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994

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